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LIST OF	KEFE	RENCES CITED BY AF	PLICAINT	Yasushi MATSUTAKA					
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		DOCUMENT NUMBER	DATE	COUNTRY			TRANSLATION YES NO		
PHD	AO	2000-032116	01/28/00	JP (with English abstract)		NO		NO	
PAD	AP	2001-111658	04/20/01	JP (with English abstract)					NO
PHD	AQ	2002-125012	04/26/02	JP (with English abstract & equivalent of US 2002/0045466) JP (with English abstract & partial English					NO
PHD	AR	2000-295324	10/20/00	translation)					NO
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OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)									
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